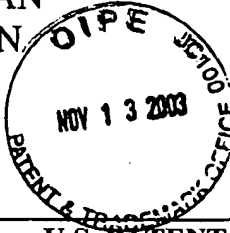


<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  (PTO-1449)				ATTY. DOCKET NO. <b>57454-963</b>		SERIAL NO. <b>Divisional of Serial No. 09/903,735</b> 10/633576	
				APPLICANT <b>Hiroshi MAEDA, ET AL.</b>			
				FILING DATE <b>August 5, 2003</b>		GROUP <b>To be assigned</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
TT	6,424,011	07/2002	Assaderaghi et al	257	350	/	
TT	6,255,151	07/2001	Fukuda et al	257	296		
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
TT	M. Igarashi, A. Harada, H. Amishiro, H. Kawashima, N. Morimoto, Y. Kusumi, T. Saito, A. Ohsaki, T. Mori, T. Fukada, Y. Toyoda, K. Higashitani, and H. Arima, "The Best Combination Of Aluminum and Copper Interconnects For a High Performance 0.18μm CMOS Logic Device," IEDM98, 1998, PP. 829-832.						
TT	J. Heidenreich, D. Edelstein, R. Goldblatt, W. Cote, C. Uzoh, N. Lustig, T. McDevitt, A. Stamper, A. Simon, J. Dukovic, R. Wachnik, H. Rathore, S. Luce, and J. Slattery, "Copper Dual <u>Damascene</u> Wiring for Sub-0.25μm CMOS Technology," PP. 13-15.						
EXAMINER				DATE CONSIDERED			
<i>Thien KMC</i>				09/03/04			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

# INFORMATION DISCLOSURE CITATION IN AN APPLICATION

ATTY. DOCKET NO.  
57454-963

SERIAL NO.  
10/633,576

APPLICANT  
Hiroshi Maeda, et al.

FILING DATE  
August 05, 2003

GROUP  
2811

(PTO-1449)

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code(s) (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number - Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
TT		1999-0062885	07/26/1999				X

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.

EXAMINER

DATE CONSIDERED

*Thom [Signature]*

09/03/04

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

*Class 1/10/03*